




Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/630,949	REED ET AL.	
	Examiner	Art Unit	
	Hiep Nguyen	2816	

ISSUE CLASSIFICATION									
ORIGINAL				CROSS REFERENCE(S)					
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
327		323		361	91.1	91.7	93.9		
INTERNATIONAL CLASSIFICATION				327					
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HIEP NGUYEN (Assistant Examiner) (Date) 01.27.05				 TUAN T. LAM PRIMARY EXAMINER (P. Examiner) (Date) 2/1/05				Total Claims Allowed: 11	
 (Legal Instruments Examiner) (Date) 2/3/05								O.G. Print Claim(s) 1	O.G. Print Fig. 5

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA				<input type="checkbox"/> T.D.				<input type="checkbox"/> R.1.47			
Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original		
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	2		32		62		92		122		152		182		
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3	11		41		71		101		131		161		191		
4	12		42		72		102		132		162		192		
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7	(15)		45		75		105		135		165		195		
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